

Application/Control No.	Applicant(s)/Patent under Reexamination
10/552,507	INOUE ET AL.
Examiner	Art Unit
LOIS ZHENG	1793

SEARCHED						
Class	Subclass	Date	Examiner			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	L			

DATE	EXMR
2/19/2009	LLZ
2/19/2009	LLZ
	2/19/2009